

Interferometry

Optical Metrology

LIGHT WAVES

- Light can be thought of as a transverse electromagnetic wave propagating through space.
- The electric and magnetic fields are linked to each other and propagate together.
- It is usually sufficient to consider only the electric field at any point.

$$\vec{E}(z, t) = \vec{E}_0 \cos \left[2\pi \left(\nu t - \frac{z}{\lambda} \right) \right]$$

where E is the amplitude of the light wave, ν is its frequency, and λ is its wavelength.

$$\vec{E}(x, y, z, t) = \vec{E}_0 \cos[wt - \vec{k} \cdot \vec{r}]$$

$$\vec{E}(x, y, z, t) = \text{Re}\{\vec{E}_0 \exp(-j\vec{k} \cdot \vec{r}) \exp(jwt)\}$$

$$\vec{E}(x, y, z, t) = \text{Re}\{\vec{A} \exp(jwt)\}$$

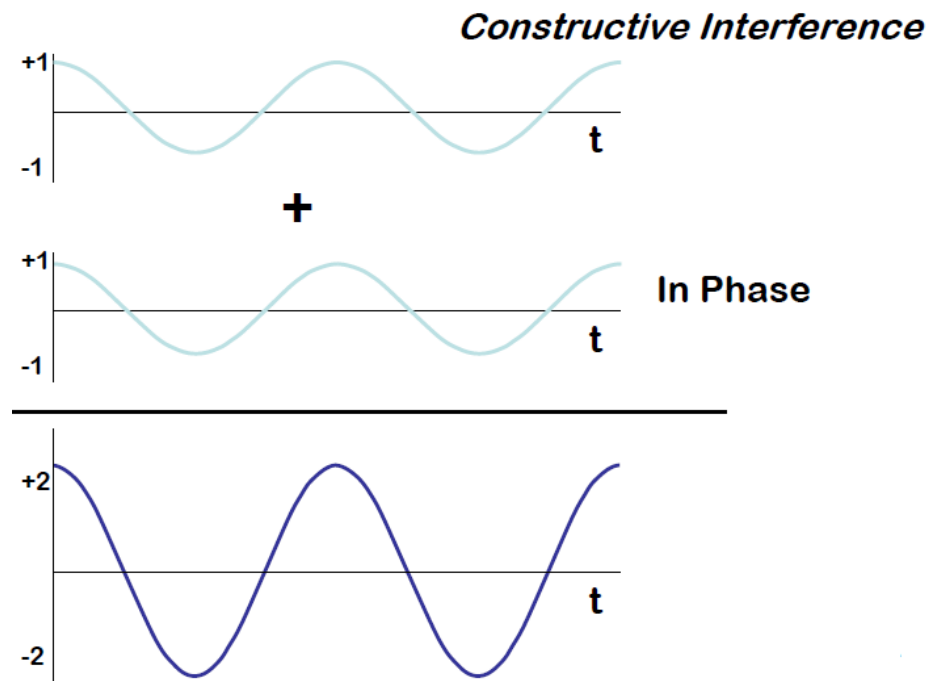
Complex exponential representation

THE INTENSITY

The most common detectors (Eye, photodiodes, multiplication tubes, photographic film, etc.) register the irradiance, which is proportional to the field amplitude absolutely squared

$$I = \frac{\epsilon v}{2} U^2$$

Superposition



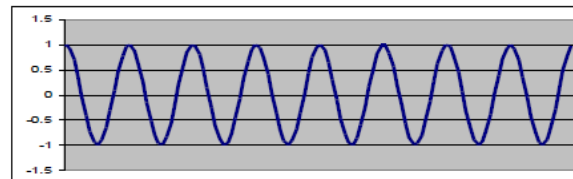
$$\vec{E}_T = \vec{E}_1 + \vec{E}_2$$

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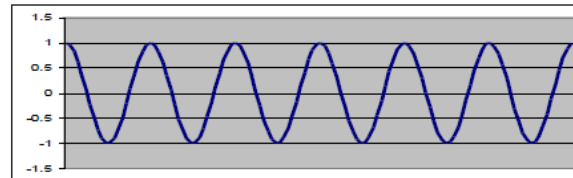
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Superposition

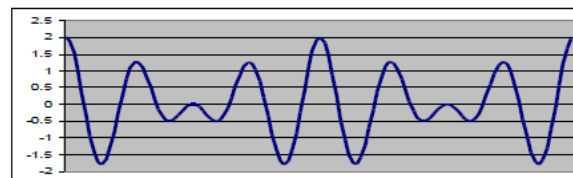


Different f

+



$$\vec{E}_T = \vec{E}_1 + \vec{E}_2$$



1) Constructive

2) Destructive

3) Neither

Interference

- Interference can occur when two or more waves overlap each other in space.
- The electromagnetic wave theory tells us that the resulting field simply becomes the superposition.
- Resulting intensity is not just $(I_1 + I_2)$.

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Assume that two waves described by

$$u_1 = U_1 e^{i\phi_1}$$

$$u_2 = U_2 e^{i\phi_2}$$

Superposition

$$u = u_1 + u_2$$

$$I = |u|^2 = |u_1 + u_2|^2 = U_1^2 + U_2^2 + 2U_1U_2 \cos(\phi_1 - \phi_2)$$

$$= I_1 + I_2 + 2\sqrt{I_1 I_2} \cos \Delta\phi$$

$$\Delta\phi = \phi_1 - \phi_2$$

Interference

$$\begin{aligned} I &= |u|^2 = |u_1 + u_2|^2 = U_1^2 + U_2^2 + 2U_1U_2 \cos(\phi_1 - \phi_2) \\ &= I_1 + I_2 + 2\sqrt{I_1I_2} \cos \Delta\phi \end{aligned}$$

$$\Delta\phi = \phi_1 - \phi_2 \quad \left\{ \begin{array}{ll} \Delta\phi = (2n + 1)\pi, & \text{for } n = 0, 1, 2, \dots \quad \text{Destructive interference} \\ \Delta\phi = 2n\pi, & \text{for } n = 0, 1, 2, \dots \quad \text{Constructive interference} \end{array} \right.$$

Coherence

- Detection of light is an averaging process in space and time.

$$I = I_1 + I_2 + 2\sqrt{I_1 I_2} |\gamma(\tau)| \cos \Delta\phi$$

$$V = \frac{I_{\max} - I_{\min}}{I_{\max} + I_{\min}} \quad \text{contrast or visibility}$$

$$I_{\max} = I_1 + I_2 + 2\sqrt{I_1 I_2} |\gamma(\tau)|$$

$$I_{\min} = I_1 + I_2 - 2\sqrt{I_1 I_2} |\gamma(\tau)|$$

$$V = \frac{2\sqrt{I_1 I_2} |\gamma(\tau)|}{I_1 + I_2}$$

$$|\gamma(0)| = 1$$

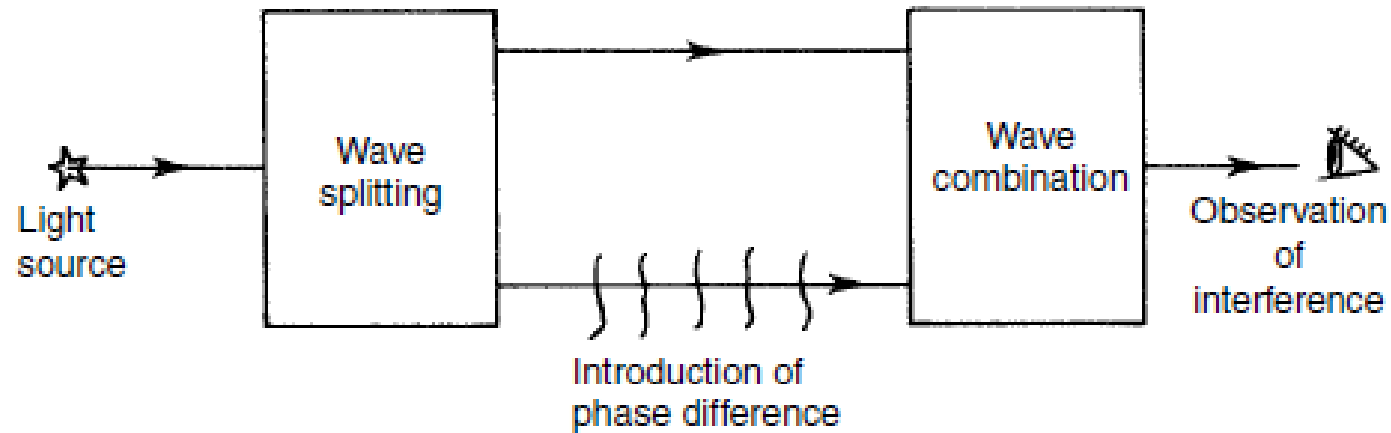
$$|\gamma(\tau_c)| = 0$$

$$0 \leq |\gamma(\tau)| \leq 1$$

Interferometry

- By measuring the distance between interference fringes over selected planes in space, quantities such as the angle and distance can be found.
- One further step would be to apply for a wave reflected from a rough surface.
- By observing the interference -can determine the surface topography.
- For smoother surfaces, however, such as optical components (lenses, mirrors, etc.) where tolerances of the order of fractions of a wavelength are to be measured, that kind of interferometry is quite common.

Interferometer



Most interferometers have the following elements:

- Light source.
- Element for splitting the light into two (or more) partial waves.
- Different propagation paths where the partial waves undergo different phase contributions.
- Element for superposing the partial waves.
- Detector for observation of the interference.

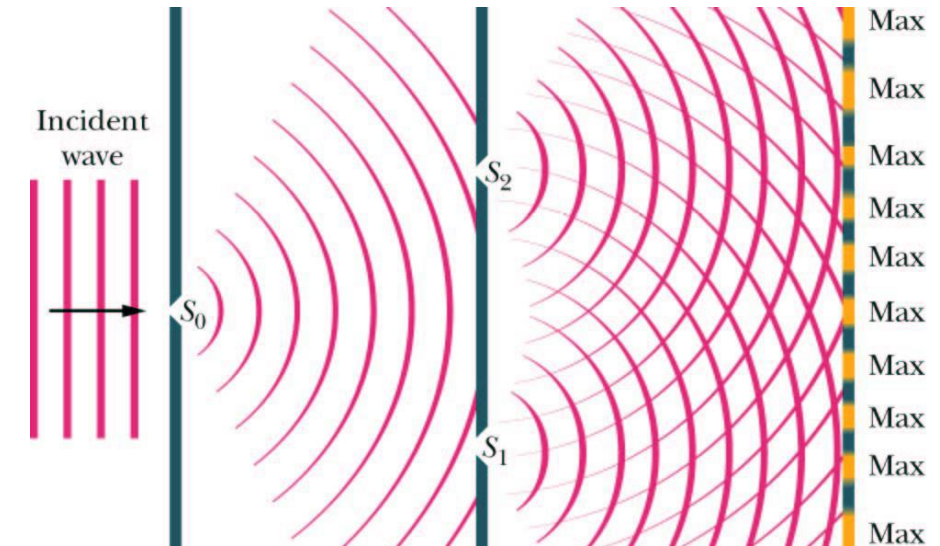
Interferometer

Depending on how the light is split, interferometers are commonly classified .

- Wavefront division interferometers.
- Amplitude division interferometers.

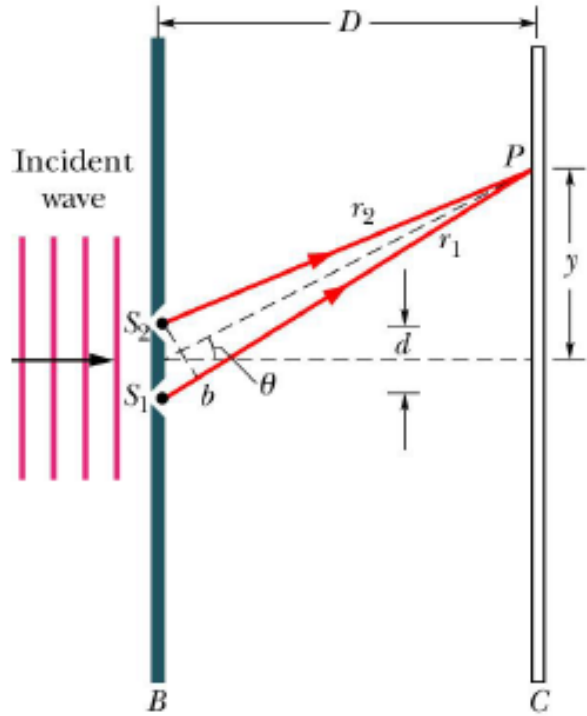
Wavefront Division Interferometers

Example of a wavefront dividing interferometer, (Thomas Young)

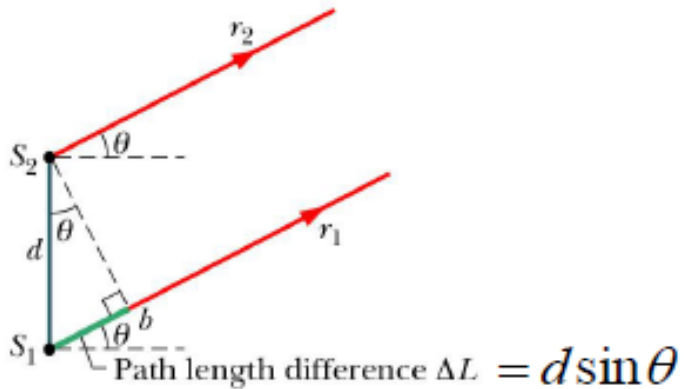


- The incident wavefront is divided by passing through two small holes at S_1 and S_2 in a screen 1.
- The emerging spherical wavefronts from S_1 and S_2 will interfere, and the pattern is observed on screen 2.
- The path length differences of the light reaching an arbitrary point x on S_2 is found from Figure.
- When the distance D between screens is much greater than the distance d between S_1 and S_2 , we have a good approximation

Wavefront Division



(a)



(b)

$$d \sin \theta = m \lambda \quad m = 0, 1, 2, 3 \dots \text{ Maximum}$$

$$\tan \theta = \frac{y_m}{D} \quad \text{or} \quad y_m = D \tan \theta \approx D \sin \theta$$

$$y_m = \frac{m \lambda D}{d}$$

Maxima

m	y_m +/-
0	0
1	$D\lambda/d$
2	$2D\lambda/d$
3	$3D\lambda/d$

Minima

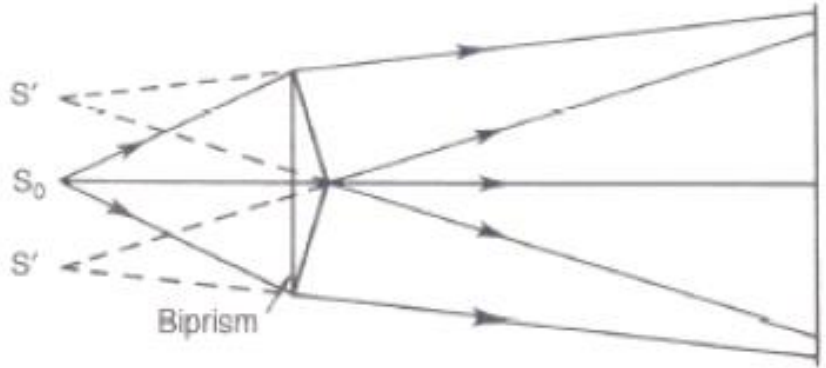
m	y_m +/-
0	$D\lambda/2d$
1	$3D\lambda/2d$
2	$5D\lambda/2d$
3	$7D\lambda/2d$

$$d \sin \theta = \left(m + \frac{1}{2}\right) \lambda \quad m = 0, 1, 2, 3 \dots \text{ Minimum}$$

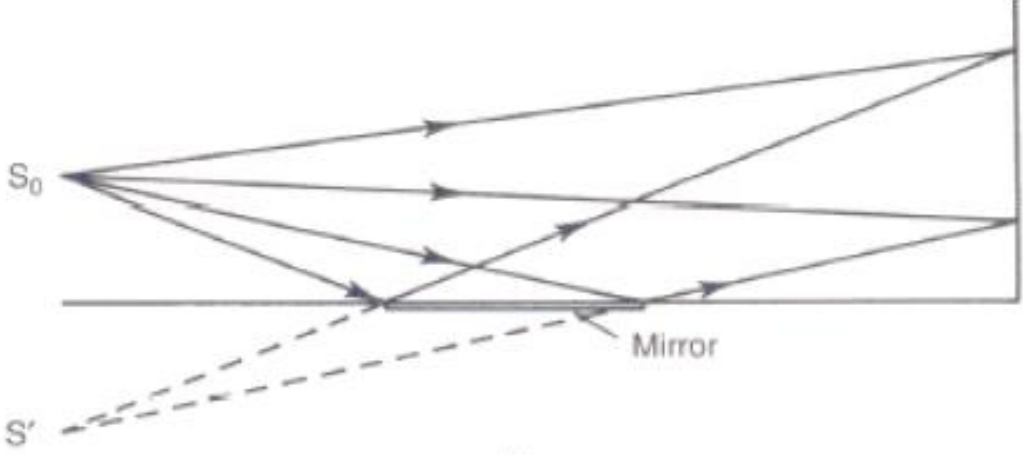
$$y_m = \frac{\left(m + \frac{1}{2}\right) \lambda D}{d}$$

Wavefront Division

Other interferometers

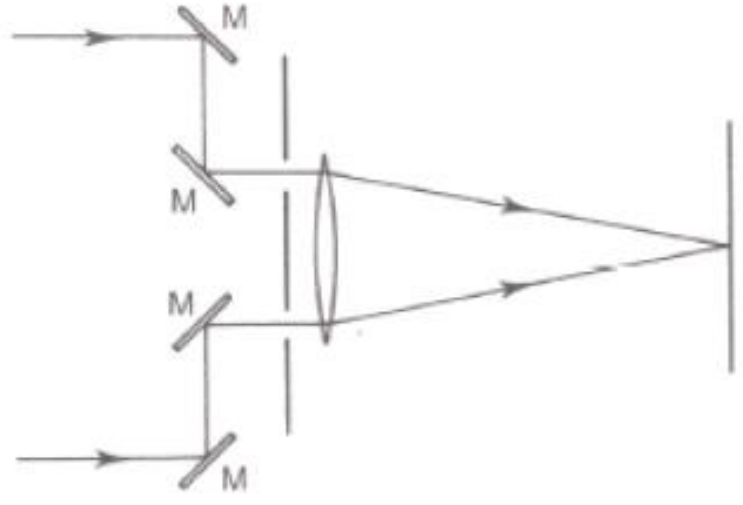


(a)



(b)

- A) Fresnel Biprism
- B) Lloyds Mirror
- C) Michelsons Stellar Interferometer

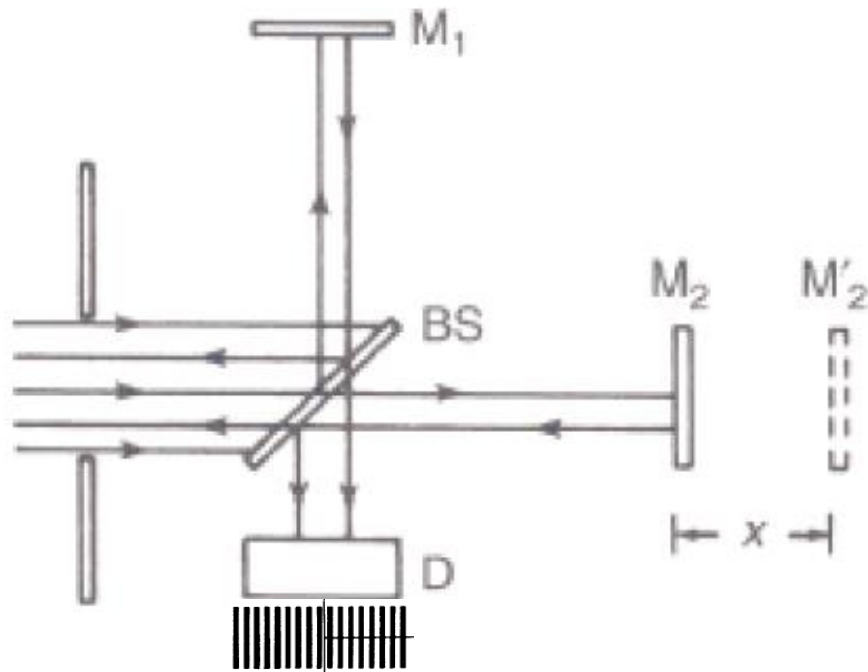


(c)

Amplitude Division Interferometers

Example of a amplitude dividing interferometer, (Michelson)

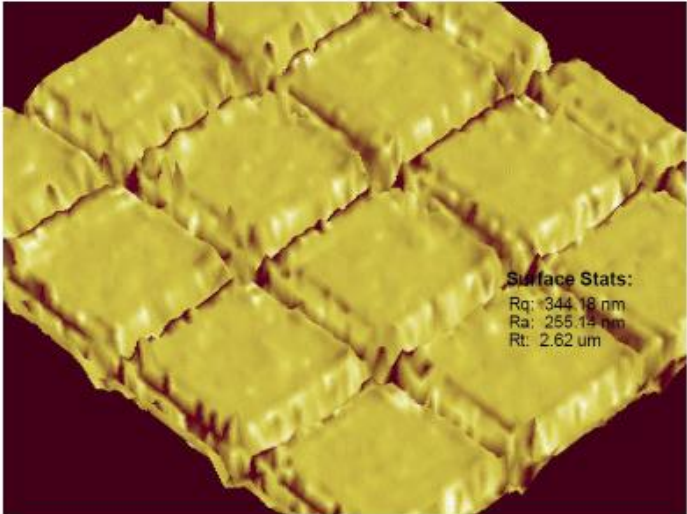
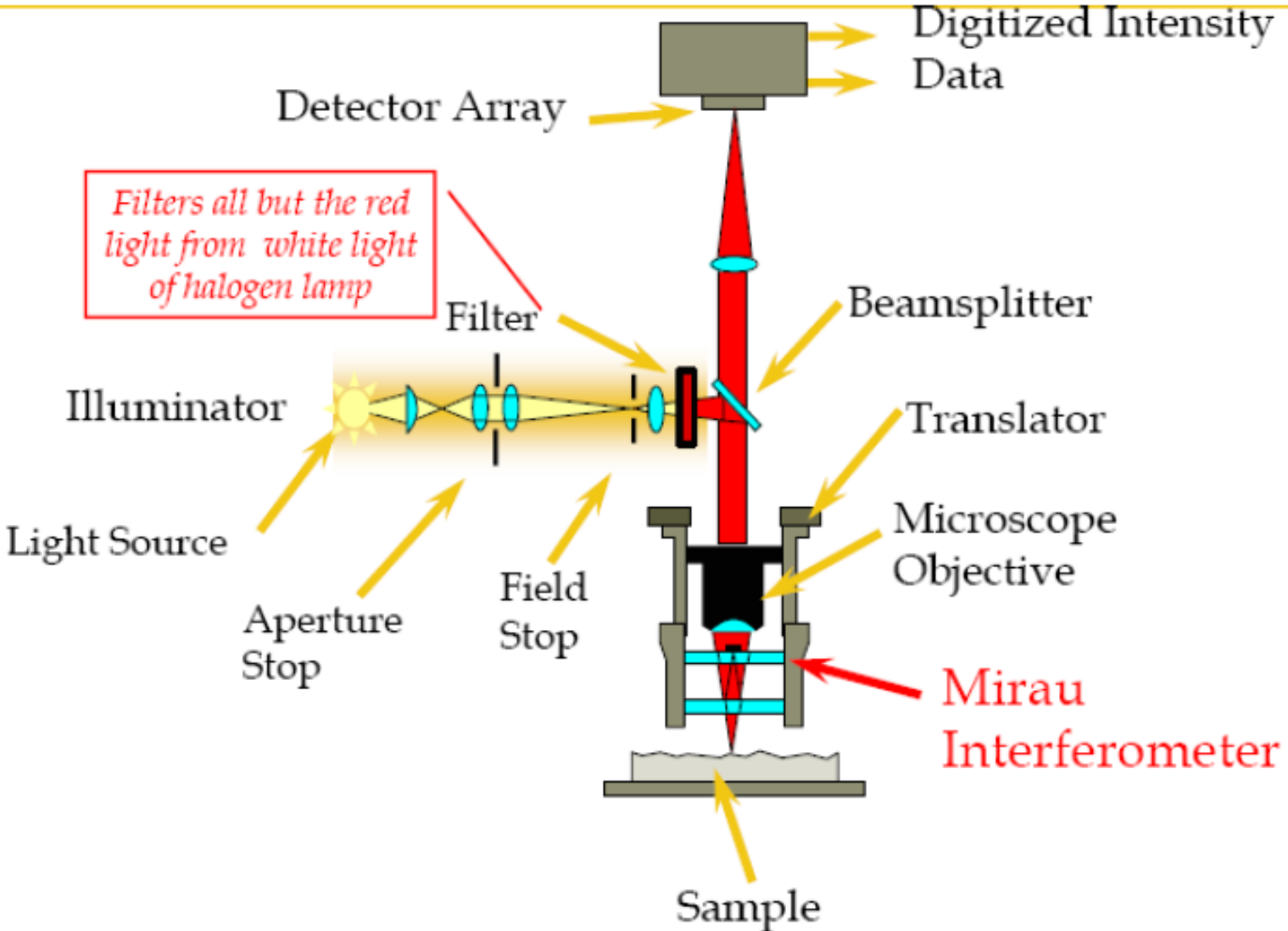
- Amplitude is divided by beam splitter BS which partly reflects and partly transmits.
- These divided light go to two mirrors M_1 and M_2 where they are reflected back.
- The reflected lights recombine to form interference on the detector D.
- The path length can be varied by moving one of the mirrors or by mounting that on movable object (movement of x give path difference of $2x$) and phase difference: $\Delta\phi = \frac{2\pi}{\lambda} 2x$



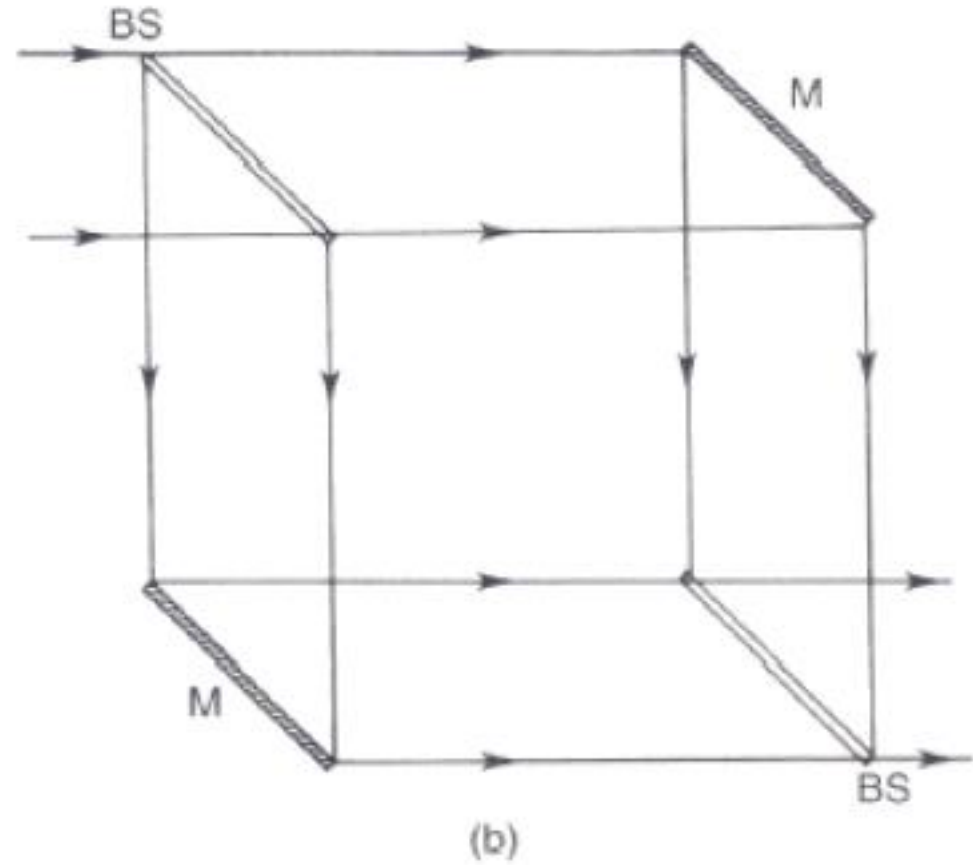
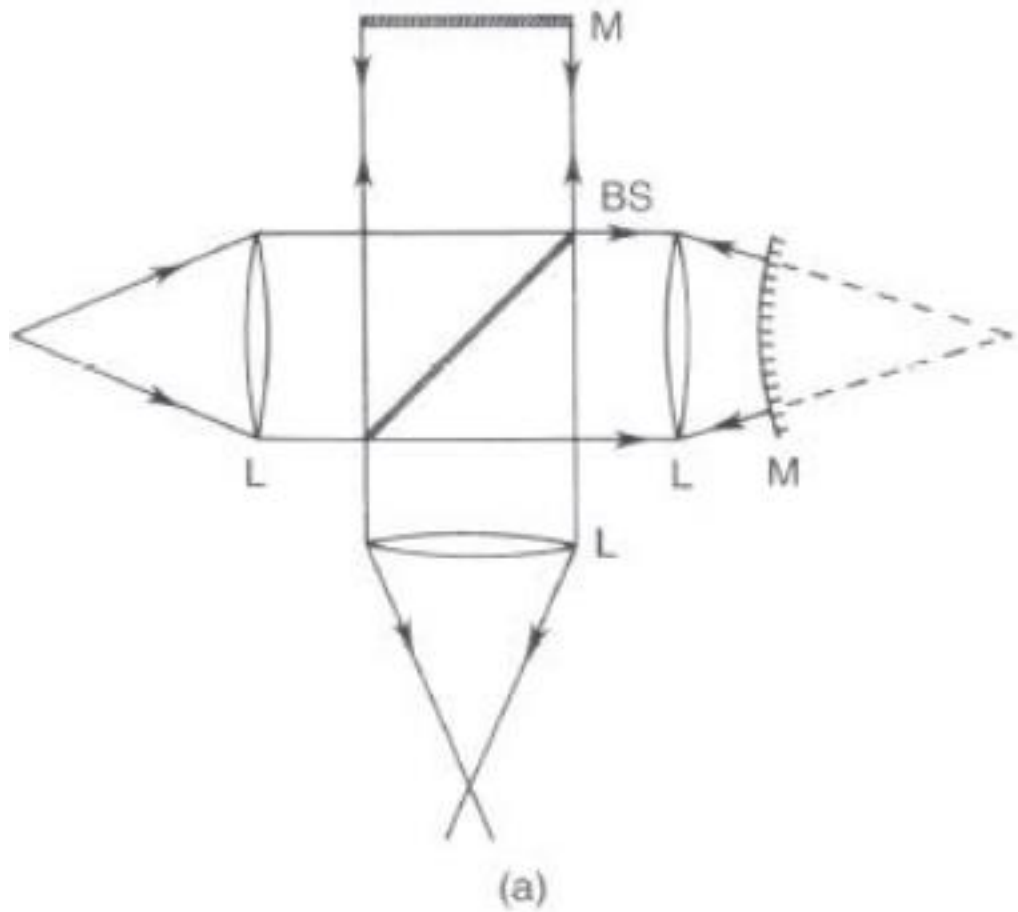
- As M_2 moves the displacement is measured by counting the number of light maxima registered by D.
- By counting the number of maxima per unit time will give the velocity of the object.

$$I(x) = 2I \left(1 + \cos \frac{4\pi x}{\lambda} \right)$$

Mirau Interferometer



Amplitude Division Interferometers



- Twyman Green Interferometer
- Mach Zehnder Interferometer

Temporal Coherence

$$I = \Delta I \left(1 + \cos \left(\frac{2\pi \nu d}{c} \right) \right) = \Delta I (1 + \cos(2\pi \nu \tau))$$

$$I = \sum_n I_n (1 + \cos(2\pi \nu_n \tau))$$

$$P(\nu) = S(\nu - \nu_0)$$

Normalized spectral distribution function of the source

$$I = \int_0^{\infty} I(\nu) (1 + \cos(2\pi \nu \tau)) d\nu = I_0 \left[1 + \int_0^{\infty} P(\nu) \cos(2\pi \nu \tau) d\nu \right]$$

$$I_0 = \int_0^{\infty} I(\nu) d\nu$$

$$\begin{aligned} \int_0^{\infty} P(\nu) \cos(2\pi \nu \tau) d\nu &= \operatorname{Re} \left\{ \int_{-\infty}^{\infty} S(\nu - \nu_0) e^{-i2\pi \nu \tau} d\nu \right\} \\ &= \operatorname{Re} \left\{ e^{-i2\pi \nu_0 \tau} \int_{-\infty}^{\infty} S(\nu) e^{-i2\pi \nu \tau} d\nu \right\} \\ &= |\gamma(\tau)| \cos(2\pi \nu_0 \tau - \varphi) \end{aligned}$$

Temporal Coherence

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$$I = I_0 [1 + |\gamma(\tau)| \cos(2\pi \nu_0 \tau - \varphi)]$$

$$\gamma(\tau) = \int_{-\infty}^{\infty} S(\nu) e^{-i2\pi \nu \tau} d\nu = |\gamma(\tau)| e^{i\varphi}$$

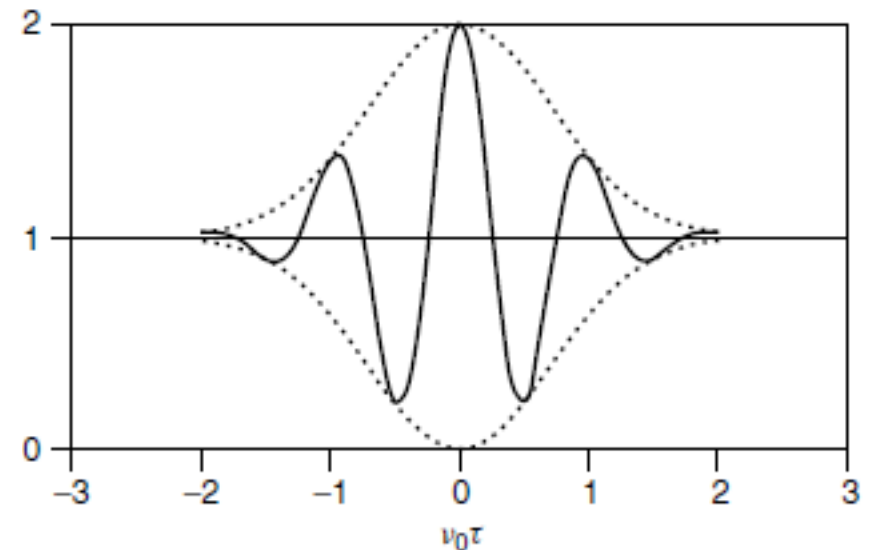
Source with a Gaussian spectral distribution function

$$P(\nu) = \frac{2\sqrt{\ln 2}}{\sqrt{\pi} \Delta \nu} \exp \left\{ - \left(2\sqrt{\ln 2} \frac{\nu - \nu_0}{\Delta \nu} \right)^2 \right\}$$

$$I = I_0 \left[1 + \exp \left\{ - \left(\frac{\pi \Delta \nu \tau}{2\sqrt{\ln 2}} \right)^2 \right\} \cos(2\pi \nu_0 \tau) \right]$$

$$\tau_c = \sqrt{\frac{2 \ln 2}{\pi}} \frac{1}{\Delta \nu} = \frac{0.664}{\Delta \nu}$$

The coherence length $L_c = c\tau_c$



Phase-Shifting Interferometry (PSI)

One of the most used methods for phase extraction is based on a phase change between the interference beams by a known value, while their amplitudes are keeping constant.

phase-shifting interferometry, phase-sampling interferometry, or phase-stepping interferometry.

$$I = a + b \cos(\phi + \psi)$$

A reference wave front is moved along its propagation direction respecting to the probe wave front changing with this the phase difference between them.

Phase-Shifting Interferometry (PSI)

Phase extraction methods

A shift of ψ_0 is made for N steps, then N intensity values I_n will be measured, (where $n = 1, \dots, N$)

$$I_n = a + b \cos(\phi + \psi_{0n})$$

Where $\psi_{0n} = 2\pi n / N$

$$I_n = A + B \cos \psi_{0n} + C \sin \psi_{0n}$$

$$A = a; \quad B = b \cos \phi; \quad C = -b \sin \phi$$

$$B = \frac{2}{N} \sum_{n=1}^N I_n \cos \psi_{0n}; \quad C = \frac{2}{N} \sum_{n=1}^N I_n \sin \psi_{0n}$$

$$\phi = \tan^{-1} \frac{-C}{B} = \tan^{-1} \frac{\sum I_n \sin \psi_{0n}}{\sum I_n \cos \psi_{0n}}$$

Three steps technique

we need a minimum of three interferograms to reconstruct the wavefront, the phase can be calculated with a phase-shift of $\frac{\pi}{2}$ per exposition.

$$I_1 = a + b \cos\left(\phi + \frac{1}{4}\pi\right)$$

$$I_2 = a + b \cos\left(\phi + \frac{3}{4}\pi\right)$$

$$I_3 = a + b \cos\left(\phi + \frac{5}{4}\pi\right)$$

$$\phi = \tan^{-1}\left(\frac{I_3 - I_2}{I_1 - I_2}\right)$$